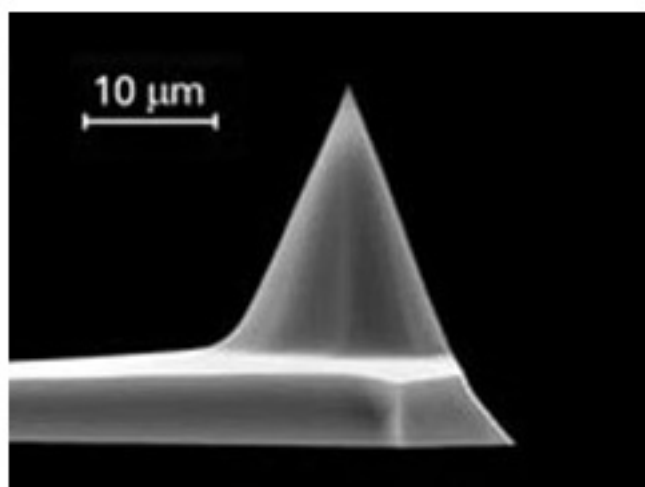


CSC17

PROBE



MikroMasch中国代理：
本原纳米仪器有限公司
Tel: 800-830-3560



SEM image of uncoated silicon SPM probe tip

Silicon etched probe tip of the CSC series has a conical shape.

Typical probe tip radius of uncoated tip
10 nm

Full tip cone angle*
40°

Tip aspect ratio
more than 3:1 (4:1 typical)

Total tip height
20..25 μm

Probe material
n-type silicon (phosphorus doped)

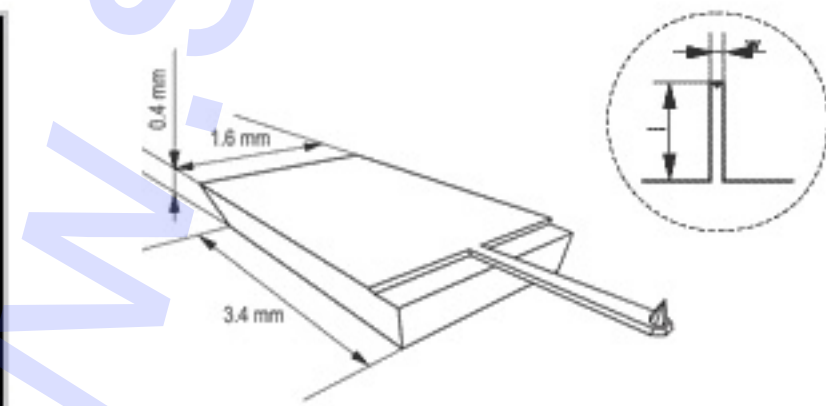
Probe bulk resistivity
0.01..0.05 Ohm*cm

*The full cone angle may be less than 40° at the last 200 nm of the tip end.

CANTILEVER



SEM image of Silicon cantilever and probe.



Schematic drawing of the probe chip.

Cantilever	Resonant Frequency, kHz			Spring Constant, N/m			Length $l \pm 5$, μm	Width $w \pm 3$, μm	Thickness $t \pm 0.5$, μm
	min	typ	max	min	typ	max			
17 Series	8.5	12	15	0.05	0.15	0.3	460	50	2.0